

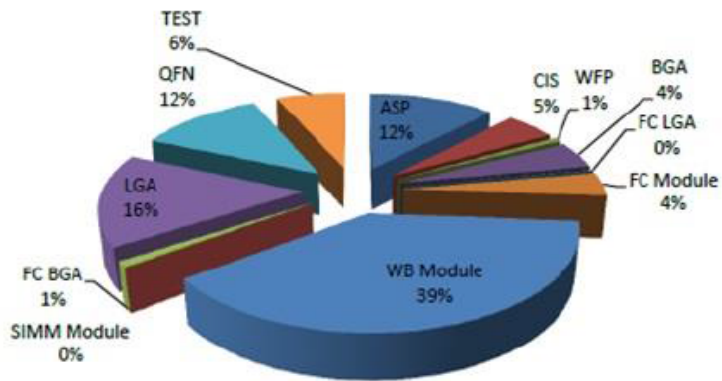
ASE Korea Capacity Summary

ASE Korea
76, Saneopdanji-gil, Paju-si,
Gyeonggi-do, Korea
Tel: 82-31-9400-114, 82-31-9400-539
Head counts: 2,791

Package Portfolio - Breakdown

- Analog Power for Automotive
- RF for digital/consumer
- MEMS for safety
- Array Packages

Production Mix by Package



Confidential Statement
This change notice is for Analog Devices, Inc.'s customers only.
Distribution or notification to third parties is prohibited.

**RELIABILITY DATA
LTM4630 ASE Korea**

5/1/2019

• J-STD-020 MSL 3 PRECONDITIONING: 192h +30°C/60%R.H. SOAK, 3x REFLOW AT +245°C PEAK					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE		NUMBER OF FAILURES
LTM4630	600 600	1905	1905		0 0
• EXTENDED PRECONDITIONING: 216h +30°C/60%R.H. SOAK, 3x REFLOW AT +245°C PEAK					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE		NUMBER OF FAILURES
LTM4630	100 100	1905	1905		0 0
• HIGH TEMPERATURE STORAGE +150°C					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS AT	NUMBER OF FAILURES
LTM4630	100 100	1905	1905	50.00 50.00	0 0
• TEMP CYCLE FROM -55°C to +125°C ⁽¹⁾					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
LTM4630	184 184	1905	1905	92.00 92.00	0 0
• THERMAL SHOCK FROM -55°C to +125°C ⁽¹⁾					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
LTM4630	184 184	1905	1905	92.00 92.00	0 0
• UNBIASED HIGHLY ACCELERATED STRESS TEST +130°C/85% R.H. ⁽¹⁾					
DEVICE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS AT +130°C	NUMBER OF FAILURES
LTM4630	199 199	1905	1905	19.10 19.10	0 0

(1) Environmental stress are preceded by J-STD-020 Level 3 Preconditioning